CHANGE NOTIFICATION



March 19, 2014

Dear Sir/Madam: PCN# 031914

Subject: Notification of Assembly Process Change for LTM8040

Please be advised that Linear Technology Corporation has made a minor change to the internal package construction to facilitate the use of one attach material for both die and components. The die attach material is changed from epoxy to solder for all dice, which is already used for attaching components in the same µModule device package. In order to use the solder die attach, the die attach paddle (DAP) has been modified by splitting the DAP into multiple pads for dice U1 and D1. The component attach pads for component C2 and C3 have also been split into multiple pads. Linear has been shipping several µModule devices using solder for die attach and component attach.

Besides these changes, no functional, parametric, mechanical, or datasheet specifications are affected and the component bill of materials remains unchanged. Similarly, there are no changes associated with the package footprint, PCB layout or product top marking, so the customer applications will be unaffected.

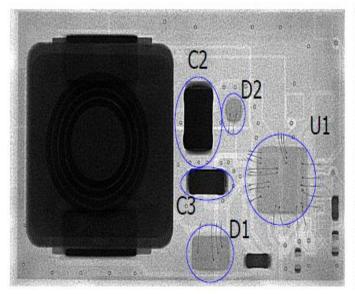
Parts incorporating the new substrate design have been fully characterized and tested for package level reliability. The change was qualified by performing extensive characterization over the full operating voltage and temperature ranges and MSL3 preconditioning. Devices from the same µModule device product families have been subjected to 1000 cycles of temperature cycles and thermal shock. Products built using the improved design are targeted for shipment after May 20, 2014.

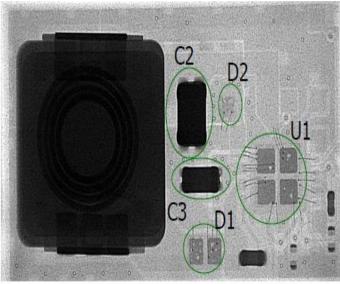
Should you have any further questions, please feel free to contact me at 408-432-1900 ext. 2077, or by E-mail <u>JASON.HU@LINEAR.COM</u>. If I do not hear from you by May 20, 2014, we will consider this change approved by your company.

Sincerely,

Jason Hu Quality Assurance Engineer

LTM8040- Current and New Design





BEFORE: EPOXY + STD DAP

AFTER CHANGE: SOLDER + WP DAP



					TECHNOLOGY				
	P	ACKAGE REL	IABILITY DAT	ΓΑ					
LTM80xx Solder Die Attach Qualification Report									
•									
3/3/2014									
OPERATING LIFE TEST									
DEVICE	Courses	O DECT	NEWECK	K DEVICE	NUMBER				
TYPE	SAMPLE SIZE	DATE CODE	NEWEST DATE CODE	HOURS	OF				
				AT +150°C	FAILURES				
LTM8008	77	1210	1210	77.00	0				
- L BTD 000 MBL 0	77	IO: 400h - 2000 IO0	VD H COAK OF DE	77.00 FLOW AT +245°C P	0				
- 3-31D-020 MSL 3	PRECONDITIONIN	16. 13211 +30*0/60*	MR.H. SUAK, SX KE	FLOW AT +245 C P					
DEVICE	SAMPLE	OLDEST	NEWEST		NUMBER				
TYPE	SIZE	DATE CODE	DATE CODE		FAILURES				
LTM8001	199	1236	1236		0				
LTM8008	462	1210	1210		ō				
LTM8021	204	1306	1306		ō				
LTM8023	204	1245	1245		0				
LTM8025	204	1245	1245		0				
LTM8027	77	1320	1320		0				
LTM8028	184	1236	1236		0				
LTM8029	246	1239	1239		0				
LTM8032	204	1302	1302		0				
LTM8033	204	1306	1306		0				
LTM8040	223	1345	1345		0				
LTM8042	230	1339	1339		0				
LTM8045	152	1225	1225		0				
LTM8047	77	1242	1242		0				
LTM8048	274	1232	1236		0				
LTM8052	358	1239	1239		0				
LTM8058	204	1239	1239		0				
LTM8061	204	1309	1309		0				
LTM8062	231	1330	1330		0				
	4,141				0				
· HIGH TEMPERAT	TURE BAKE at +15	0°C							
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER				
TYPE	SIZE	DATE CODE	DATE CODE	HOURS AT +150°C	OF FAILURES				
				A1 +150°C	PALUNES				
LTM8001	25	1236	1236	25.00	0				
LTM8008	77	1210	1210	77.00	Ö				
LTM8021	50	1306	1306	50.00	ő				
LTM8023	50	1245	1245	50.00	ō				
LTM8025	50	1245	1245	50.00	ō				
LTM8029	50	1239	1239	50.00	0				
LTM8032	74	1302	1302	74.00	0				
LTM8033	77	1306	1306	77.00	0				
LTM8042	77	1339	1339	77.00	0				
LTM8045	50	1225	1225	50.00	0				
LTM8052	50	1239	1239	50.00	0				
LTM8058	50	1239	1239	50.00	0				
LTM8062	77	1330	1330	77.00	0				
	757	L		757.00	0				
· HIGHLY ACCELE	RATED STRESS T	EST (+130°C/85%R	.H. W BIAS)						
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER				
TYPE	SIZE	DATE CODE	DATE CODE	HOURS AT +85°C	OF FAILURES				
				A1 405 C	174201420				
LTM8008	46	1210	1210	88.32	0				
ET MOUUS	46	1210	1210	88.32	0				
· UNBIASED HIGH	LY ACCELERATED	STRESS TEST /+	130°C/85%R H 1 (1)	22.22					
					NAME OF THE PERSON OF THE PERS				
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE HOURS	NUMBER OF				
TYPE	SIZE	DATE CODE	DATE CODE	AT +130°C	FAILURES				
LTM8001	43	1236	1236	4.13	0				
LTM8023	50	1245	1245	4.80	0				
LTM8025	50	1245	1245	4.80	0				
LTM8028	30	1236	1236	2.88	0				
LTM8029	70	1239	1239	6.72	0				
LTM8032	50	1302	1302	4.80	0				
LTM8033	50	1306	1306	4.80	0				
LTM8042	77	1339	1339	7.39	0				
LTM8045	49	1225	1225	8.23	0				
LTM8052	50	1239	1239	4.80	0				
LTM8058	50	1239	1239	4.80	0				
	50	1309	1309	4.80	0				
LTM8061	I	l							
LTM8061 LTM8062	77 742	1330	1330	7.39 72.55	0				



					TECHNOLOGY				
		ACKACE DEL	LADIL ITY DAT						
		ACKAGE REL							
LTM80xx Solder Die Attach Qualification Report									
3/3/2014									
• TEMPERATURE/HUMIDITY STORAGE (+85°C/85%R.H.) (1)									
DEVICE		0.000	Leuran	K DEVICE	NUMBER				
TYPE	SAMPLE SIZE	DATE CODE	NEWEST DATE CODE	HOURS	OF FAILURES				
				AT +85°C	PALURES				
1.7110000		4040	4040	77.00					
LTM8008	77	1210	1210	77.00	0				
LTM8062	50	1330	1330	25.00	0				
127 102.00 0 • TEMP CYCLE FROM -65°C to +150°C (1)									
· TEMP CTCLE FR	OM -65°C 10 +150°								
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER OF				
TYPE	SIZE	DATE CODE	DATE CODE	CYCLES	FAILURES				
LTM8008	231	1210	1210	231.00	0				
LTM8032	77	1302	1302	77.00	0				
LTM8033	77	1306	1306	77.00	0				
LTM8052	77	1239	1239	77.00	0				
LTM8061	77	1309	1309	77.00	0				
	539	-		539.00	0				
• TEMP CYCLE FROM -55°C to +125°C (1)									
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER				
TYPE	SAMPLE	DATE CODE	DATE CODE	CYCLES	OF FAILURES				
					PALURES				
LTM8001	77	1236	1236	77.00	0				
LTM8021	77	1306	1306	77.00	0				
LTM8023	77	1245	1245	77.00	0				
LTM8025	77	1245	1245	77.00	0				
LTM8027	77	1320	1320	77.00	Ö				
LTM8028	77	1236	1236	77.00	ő				
LTM8029	77	1239	1239	77.00	ő				
LTM8042	77	1339	1339	77.00	ō				
LTM8045	77	1225	1225	77.00	0				
LTM8047	77	1242	1242	77.00	0				
LTM8048	102	1232	1236	140.50	0				
LTM8052	77	1239	1239	77.00	0				
LTM8058	77	1239	1239	77.00	0				
LTM8062	77	1330	1330	77.00	0				
	1,103			1,141.50	0				
 THERMAL SHOC 	K FROM -65°C to +	-150°C ⁽¹⁾							
					NUMBER				
DEVICE TYPE	SAMPLE SIZE	DATE CODE	DATE CODE	K DEVICE CYCLES	OF FAILURES				
					PALONES				
LTM8008	231	1210	1210	231.00	0				
LTM8032	77	1302	1302	77.00	0				
LTM8033	77	1302	1306	77.00	0				
LTM8052	77	1239	1239	77.00	ő				
LTM8061	77	1309	1309	77.00	ō				
	539			539.00	0				
· THERMAL SHOC	K FROM -55°C to +	-125°C ⁽¹⁾							
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER				
TYPE	SAMPLE	DATE CODE	DATE CODE	CYCLES	OF FAILURES				
					PALURES				
LTM8001	77	1236	1236	77.00	0				
LTM8021	77	1306	1306	77.00	0				
LTM8023	77	1245	1245	77.00	0				
LTM8025	77	1245	1245	77.00	0				
LTM8028	77	1236	1236	77.00	ő				
LTM8029	77	1239	1239	77.00	Ö				
LTM8042	76	1339	1339	77.00	0				
LTM8045	75	1225	1225	75.00	0				
LTM8048	126	1232	1236	126.00	0				
LTM8052	77	1239	1239	77.00	0				
LTM8058	77	1239	1239	77.00	0				
LTM8062	77	1330	1330	77.00	0				
BOARD *******	970			971.00	0				
• BOARD MOUNT TEMP CYCLE FROM -40°C to +125°C									
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER OF				
TYPE	SIZE	DATE CODE	DATE CODE	CYCLES	FAILURES				
LTM8008	15	1210	1210	22.50	0				
	15			22.50	0				
(1) Environmental stress are preceded by JEDEC Level 3 Preconditioning: 192h 30 C/60% R.H. soak, followed by 3x									
Reflow at 245°C									